the wafer has a peak-to-valley flatness less than about 1 µinch.

- 16. (Twice Amended) The wafer of claim 11 wherein the surface of the wafer has a surface flatness less than about 1 μ inch.
- 17. (Twice Amended) The wafer of claim 11 wherein the array of glide transducers are mounted on a wafer surface opposite to the surface of the wafer having the air bearing surfaces formed thereon.
- 18. (Twice Amended) The wafer of claim 11 wherein the surface of the wafer has a flatness less than about 0.5 µinch.
- 19. (Twice Amended) A glide head formed from the a wafer comprising a plurality of rows and a plurality of columns of glide portions having a plurality of air bearing surfaces formed on a surface of the wafer and an array of glide transducers on the wafer and the glide head formed from one of said glide portions.
- 23. (Amended) The wafer of claim 11 wherein the array of glide transducers are formed on the surface of the wafer having the air bearing surfaces formed thereon.
- 25. (Amended) The wafer of claim 24 wherein the thermal transducers of the array of thermal transducers are formed of magnetoresistive sensors.

Please add new claim 26 as follows:

26. (New) The wafer of claim 11 wherein the air bearing surfaces of the plurality of rows and the plurality of columns of glide portions are formed using one of or a combination of saw cutting, milling or deposition techniques.